



3. (currently amended)     ~~An The x-ray examination apparatus as claimed in Claim of~~  
~~claim 1, and further~~ comprising a collimator between the x-ray detector ~~source~~ and the x-ray detector,  
wherein the collimator ~~comprises~~ has an x-ray absorbing member ~~which that~~ is spatially registered  
with the peripheral region of the photoconductor.

4. (currently amended).     ~~An The x-ray examination apparatus as claimed in Claim of~~  
~~claim 1, wherein and wherein~~ the selection system ~~includes~~ has an encompassing electrode which  
~~surrounds at least substantially surrounding~~ the central region and which is electrically connected to  
the read-out elements of the peripheral group.

5. (currently amended)     ~~An The x-ray examination apparatus as claimed in Claim of~~  
~~claim 1, wherein~~ collecting electrodes of read-out elements of the peripheral group are smaller sized  
than collecting electrodes of the read-out elements the central group.

6. (currently amended)     ~~An The x-ray examination apparatus as claimed in Claim of~~  
~~claim 1, wherein~~ the selection system electrically isolates the peripheral group of read-out elements  
from the output circuit.

7. (currently amended)     ~~An The x-ray examination apparatus as claimed in Claim of~~  
~~claim 1, wherein~~ the photoconductor is a continuous semiconductor layer or the photoconductor  
includes a plurality of crystalline semiconductor elements.

8. (currently amended) ~~As The x-ray examination apparatus as claimed in Claim of~~  
claim 7, wherein the semiconductor layer or the semiconductor elements contain a photoconducting  
material from the group of Cadmium Zinc Telluride, Mercury Iodide or Lead Oxide.